

## **TEM Measurements**

**Date:**

**Name:**

**Phone:**

**Department:**

**Working group:**

**Name of the sample(s):**

### **Chemical composition:**

**Please specify the voltage to be used (based on the sensitivity of your sample to the beam)**

60 kV      80 kV      200 kV

**Please mark by means of which techniques the pre-characterization has been done:**

SEM     AFM       X-ray diffraction     other   

### **TEM sample preparation:**

Please specify the solvent to be used for making a dispersion in case you want your sample to be drop-casted onto a TEM grid. If you require specific preparation techniques (ultramicrotomy, staining etc.) or do not know what the best way would be to prepare your sample, please contact the EM technical staff.

Solvent:  ethanol     acetone     water     other   

**Additional information:** (e.g. sensitivity to the beam, particle size, etc.):

**What is the main goal of using JEOL ARM:** (please describe the specific problem and mark which operation mode you would like to use):

TEM, HR-TEM       STEM       SAED       EDX